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Preface

The hallmark of the CRC Press “Electronics Engineering Series” of books is their depth of coverage on targeted subjects. Even the more general-interest publication of the series—*The Electronics Handbook*—covers the entire realm of electronics in exceptional detail.

This book is a departure from those that have gone before it. *The Resource Handbook of Electronics* is intended to provide quick access to basic information, mostly through figures and tables. For each of the 20-plus chapters, a broad-brush overview is given, followed in most cases by extensive tabular data. *The Resource Handbook of Electronics* is intended for readers who need specific data at their fingertips, accessible in a convenient format.

This book is intended for engineers, technicians, operators, and technical managers involved in the specification, design, installation, operation, maintenance, and management of electronics facilities. The book is designed to be a hands-on pocket guide that holds solutions to specific problems. In this regard, it is a companion publication to *The Electronics Handbook* and the other books in the series. For readers who need extensive background on a given subject, *The Electronics Handbook* and its related works provide the necessary level of detail. For readers who need a broad overview of the subject and essential data relating to it, *The Resource Handbook of Electronics* is the ideal publication.

This book is organized in a logical sequence that begins with fundamental electrical properties and builds to higher levels of sophistication from one chapter to the next. Chapters are devoted to all of the most common components and devices, in addition to higher-level applications of those components.

Among the extensive data contained in *The Resource Handbook of Electronics* are

- **Frequency assignments**—A complete and up-to-date listing of frequencies used by various services in the U.S. and elsewhere
- **Glossary of terms**—An extensive dictionary of electronic terms, including abbreviations and acronyms
- **Conversion factors**—Detailed tables covering all types of conversion requirements in the field of electronics

The Resource Handbook of Electronics is the most detailed publication of its kind. I trust you will find it useful on the job, day in and day out.

Jerry C. Whitaker
Morgan Hill, California

For updated information on this and other engineering books, visit the author's
Internet site
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About the Author

Jerry Whitaker is a technical writer based in Morgan Hill, California, where he operates the consulting firm *Technical Press*. Mr. Whitaker has been involved in various aspects of the communications industry for more than 25 years. He is a Fellow of the Society of Broadcast Engineers and an SBE-certified Professional Broadcast Engineer. He is also a member and Fellow of the Society of Motion Picture and Television Engineers, and a member of the Institute of Electrical and Electronics Engineers. Mr. Whitaker has written and lectured extensively on the topic of electronic systems installation and maintenance.

Mr. Whitaker is the former editorial director and associate publisher of *Broadcast Engineering* and *Video Systems* magazines. He is also a former radio station chief engineer and TV news producer.

Mr. Whitaker is the author of a number of books, including:

- *The Communications Facility Design Handbook*, CRC Press, 2000.
- *Power Vacuum Tubes Handbook*, 2nd edition, CRC Press, 1999.
- *AC Power Systems*, 2nd edition, CRC Press, 1998.
- *DTV: The Revolution in Electronic Imaging*, 2nd edition, McGraw-Hill, 1999.
- Editor-in-Chief, *NAB Engineering Handbook*, 9th edition, National Association of Broadcasters, 1999.
- Editor-in-Chief, *The Electronics Handbook*, CRC Press, 1996.
- Coauthor, *Communications Receivers: Principles and Design*, 2nd edition, McGraw-Hill, 1996.
- *Electronic Displays: Technology, Design, and Applications*, McGraw-Hill, 1994.
- Coeditor, *Standard Handbook of Video and Television Engineering*, 3rd edition, McGraw-Hill, 2000.
- Coeditor, *Information Age Dictionary*, Intertec/Bellcore, 1992.
- *Maintaining Electronic Systems*, CRC Press, 1991.
- *Radio Frequency Transmission Systems: Design and Operation*, McGraw-Hill, 1990.

Mr. Whitaker has twice received a Jesse H. Neal Award *Certificate of Merit* from the Association of Business Publishers for editorial excellence. He also has been recognized as *Educator of the Year* by the Society of Broadcast Engineers.

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For baby
Ashley Grace Whitaker
The journey begins...

Whitaker, Jerry C. "Fundamental Electrical Properties"
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Fundamental Electrical Properties

1.1 Introduction

The atomic theory of matter specifies that each of the many chemical elements is composed of unique and identifiable particles called atoms. In ancient times only 10 were known in their pure, uncombined form; these were carbon, sulfur, copper, antimony, iron, tin, gold, silver, mercury, and lead. Of the several hundred now identified, less than 50 are found in an uncombined, or chemically free, form on earth.

Each atom consists of a compact nucleus of positively and negatively charged particles (protons and electrons, respectively). Additional electrons travel in well-defined orbits around the nucleus. The electron orbits are grouped in regions called *shells*, and the number of electrons in each orbit increases with the increase in orbit diameter in accordance with quantum-theory laws of physics. The diameter of the outer orbiting path of electrons in an atom is in the order of one-millionth (10^{-6}) millimeter, and the nucleus, one-millionth of that. These typical figures emphasize the minute size of the atom.

1.2 Electrical Fundamentals

The nucleus and the free electrons for an iron atom are shown in the schematic diagram in [Figure 1.1](#). Note that the electrons are spinning in different directions. This rotation creates a magnetic field surrounding each electron. If the number of electrons with positive spins is equal to the number with negative spins, then the net field is zero and the atom exhibits no magnetic field.

In the diagram, although the electrons in the first, second, and fourth shells balance each other, in the third shell five electrons have clockwise positive spins, and one a counterclockwise negative spin, which gives the iron atom in this particular electron configuration a cumulative *magnetic effect*.

The parallel alignment of the electron spins over regions, known as *domains*, containing a large number of atoms. When a magnetic material is in a demagnetized state, the direction of magnetization in the domain is in a random order. Magnetization by an

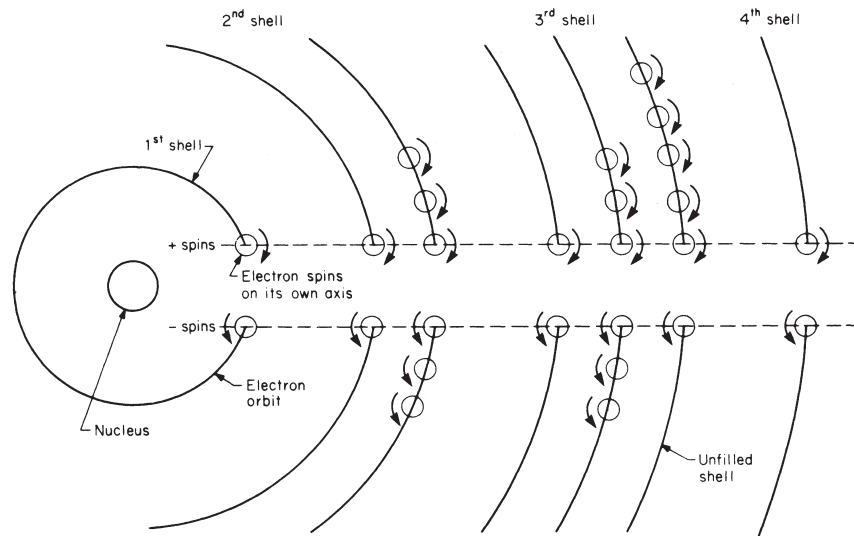


Figure 1.1 Schematic of the iron (Fe) atom.

external field takes place by a change or displacement in the isolation of the domains, with the result that a large number of the atoms are aligned with their charged electrons in parallel.

1.2.1 Conductors and Insulators

In some elements, such as copper, the electrons in the outer shells of the atom are so weakly bound to the nucleus that they can be released by a small electrical force, or voltage. A voltage applied between two points on a length of a metallic conductor produces the flow of an electric current, and an electric field is established around the conductor. The conductivity is a constant for each metal that is unaffected by the current through or the intensity of any external electric field.

In some nonmetallic materials, the free electrons are so tightly bound by forces in the atom that, upon the application of an external voltage, they will not separate from their atom except by an electrical force strong enough to destroy the insulating properties of the material. However, the charges will realign within the structure of their atom. This condition occurs in the insulating material (dielectric) of a capacitor when a voltage is applied to the two conductors encasing the dielectric.

Semiconductors are electronic conducting materials wherein the conductivity is dependent primarily upon impurities in the material. In addition to negative mobile charges of electrons, positive mobile charges are present. These positive charges are called *holes* because each exists as an absence of electrons. Holes (+) and electrons (–),

because they are oppositely charged, move in opposite directions in an electric field. The conductivity of semiconductors is highly sensitive to, and increases with, temperature.

1.2.2 Direct Current (dc)

Direct current is defined as a unidirectional current in which there are no significant changes in the current flow. In practice, the term frequently is used to identify a voltage source, in which case variations in the load can result in fluctuations in the current but not in the direction.

Direct current was used in the first systems to distribute electricity for household and industrial power. For safety reasons, and the voltage requirements of lamps and motors, distribution was at the low nominal voltage of 110. The losses in distribution circuits at this voltage seriously restricted the length of transmission lines and the size of the areas that could be covered. Consequently, only a relatively small area could be served by a single generating plant. It was not until the development of alternating-current systems and the voltage transformer that it was feasible to transport high levels of power at relatively low current over long distances for subsequent low-voltage distribution to consumers.

1.2.3 Alternating Current (ac)

Alternating current is defined as a current that reverses direction at a periodic rate. The average value of alternating current over a period of one cycle is equal to zero. The effective value of an alternating current in the supply of energy is measured in terms of the root mean square (rms) value. The rms is the square root of the square of all the values, positive and negative, during a complete cycle, usually a sine wave. Because rms values cannot be added directly, it is necessary to perform an rms addition as shown in the equation:

$$V_{rms\ total} = \sqrt{V_{rms\ 1}^2 + V_{rms\ 2}^2 + \dots + V_{rms\ n}^2} \quad (1.1)$$

As in the definition of direct current, in practice the term frequently is used to identify a voltage source.

The level of a sine-wave alternating current or voltage can be specified by two other methods of measurement in addition to rms. These are *average* and *peak*. A sine-wave signal and the rms and average levels are shown in [Figure 1.2](#). The levels of complex, symmetrical ac signals are specified as the peak level from the axis, as shown in the figure.

1.2.4 Static Electricity

The phenomenon of static electricity and related potential differences concerns configurations of conductors and insulators where no current flows and all electrical

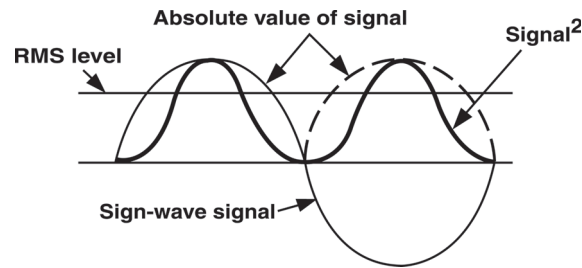


Figure 1.2 Root mean square (rms) measurements. The relationship of rms and average values is shown.

forces are unchanging; hence the term *static*. Nevertheless, static forces are present because of the number of excess electrons or protons in an object. A static charge can be induced by the application of a voltage to an object. A flow of current to or from the object can result from either a breakdown of the surrounding nonconducting material or by the connection of a conductor to the object.

Two basic laws regarding electrons and protons are:

- Like charges exert a repelling force on each other; electrons repel other electrons and protons repel other protons
- Opposite charges attract each other; electrons and protons are attracted to each other

Therefore, if two objects each contain exactly as many electrons as protons in each atom, there is no electrostatic force between the two. On the other hand, if one object is charged with an excess of protons (deficiency of electrons) and the other an excess of electrons, there will be a relatively weak attraction that diminishes rapidly with distance. An attraction also will occur between a neutral and a charged object.

Another fundamental law, developed by Faraday, governing static electricity is that all of the charge of any conductor not carrying a current lies in the surface of the conductor. Thus, any electric fields external to a completely enclosed metal box will not penetrate beyond the surface. Conversely, fields within the box will not exert any force on objects outside the box. The box need not be a solid surface; a conduction cage or grid will suffice. This type of isolation frequently is referred to as a *Faraday shield*.

1.2.5 Noise in Electronic Circuits

Noise has become the standard term for signals that are random and that are combined with the circuit signal to affect the overall performance of a system. As the study of noise has progressed, engineers have come to realize that there are many sources of noise in circuits. The following definitions are commonly used in discussions of circuit noise:

- *White noise*: a signal that has its energy evenly distributed over the entire frequency spectrum, within the frequency range of interest (typically below frequencies in the infrared range). Because *white noise* is totally random, it may seem inappropriate to refer to its frequency range, because it is not really periodic in the ordinary sense. Nevertheless, by examining an oscilloscope trace of white noise, it can be verified that every trace is different, as the noise never repeats itself, and yet each trace looks the same. There is a strong theoretical foundation to represent the frequency content of such signals as covering the frequency spectrum evenly. In this way the impact on other periodic signals can be analyzed. The term white noise arises from the fact that, similar to white light, which has equal amounts of all light frequencies, white noise has equal amounts of noise at all frequencies within circuit operating ranges.
- *Interference*: the name given to any predictable, periodic signal that occurs in an electronic circuit in addition to the signal the circuit is designed to process. This is distinguished from a noise signal by the fact that it occupies a relatively small frequency range, and because it is predictable it can often be filtered out. Usually, interference comes from another electronic system such as an interfering radio source.
- *Thermal noise*: any noise that is generated within a circuit and is temperature-dependent. This signal usually is the result of the influence of temperature directly on the operating characteristics of circuit components, which because of the random motion of molecules as a result of temperature, in turn creates a random fluctuation of the signal being processed.
- *Shot noise*: a type of circuit noise that is not temperature-dependent, and is not white noise in the sense that it tends to diminish at higher frequencies. This noise usually occurs in components whose operation depends on a mean *particle residence time* for the active electrons within the device. The *cutoff frequency* above which noise disappears is closely related to the inverse of this characteristic particle residence time.

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1.5 Tabular Data

Table 1.1 Symbols and Terminology for Physical and Chemical Quantities: Classical Mechanics (*From [1]. Used with permission.*)

Name	Symbol	Definition	SI unit
mass	m		kg
reduced mass	μ	$\mu = m_1 m_2 / (m_1 + m_2)$	kg
density, mass density	ρ	$\rho = m/V$	kg m^{-3}
relative density	d	$d = \rho/\rho^\theta$	1
surface density	ρ_A, ρ_S	$\rho_A = m/A$	kg m^{-2}
specific volume	v	$v = V/M = 1/\rho$	$\text{m}^3 \text{kg}^{-1}$
momentum	$\mathbf{p}$	$\mathbf{p} = m\mathbf{v}$	kg ms^{-1}
angular momentum, action	L	$L = \mathbf{r} \times \mathbf{p}$	J s
moment of inertia	I, J	$I = \sum m_i r_i^2$	kg m^2
force	$\mathbf{F}$	$\mathbf{F} = d\mathbf{p}/dt = m\mathbf{a}$	N
torque, moment of a force	$T, (\mathbf{M})$	$T = \mathbf{r} \times \mathbf{F}$	N m
energy	E		J
potential energy	E_p, V, Φ	$E_p = -\int \mathbf{F} \cdot d\mathbf{s}$	J
kinetic energy	E_k, T, K	$E_k = (1/2)mv^2$	J
work	W, w	$W = \int \mathbf{F} \cdot d\mathbf{s}$	J
Hamilton function	H	$H(q, p)$ $= T(q, p) + V(q)$	J
Lagrange function	L	$L(q, \dot{q})$ $= T(q, \dot{q}) - V(q)$	J
pressure	p, P	$p = F/A$	Pa, N m^{-2}
surface tension	γ, σ	$\gamma = dW/dA$	$\text{N m}^{-1}, \text{J m}^{-2}$
weight	$G, (W, P)$	$G = mg$	N
gravitational constant	G	$F = Gm_1 m_2 / r^2$	$\text{N m}^2 \text{kg}^{-2}$
normal stress	σ	$\sigma = F/A$	Pa
shear stress	τ	$\tau = F/A$	Pa
linear strain, relative elongation	ε, e	$\varepsilon = \Delta l/l$	1
modulus of elasticity, Young's modulus	E	$E = \sigma/\varepsilon$	Pa
shear strain	γ	$\gamma = \Delta x/d$	1
shear modulus	G	$G = \tau/\gamma$	Pa
volume strain, bulk strain	θ	$\theta = \Delta V/V_0$	1
bulk modulus, compression modulus	K, μ	$K = -V_0(dp/dV)$ $\tau_{x,z} = \eta(dv_x/dz)$	Pa Pa s
viscosity, dynamic viscosity	η		
fluidity	ϕ	$\phi = 1/\eta$	$\text{m kg}^{-1} \text{s}$
kinematic viscosity	ν	$\nu = \eta/\rho$	$\text{m}^2 \text{s}^{-1}$
friction coefficient	$\mu, (f)$	$F_{\text{frict}} = \mu F_{\text{norm}}$	1
power	P	$P = dW/dt$	W
sound energy flux	P, P_a	$P = dE/dt$	W
acoustic factors			
reflection factor	ρ	$\rho = P_r/P_0$	1
acoustic absorption factor	$\alpha_a, (\alpha)$	$\alpha_a = 1 - \rho$	1
transmission factor	τ	$\tau = P_{\text{tr}}/P_0$	1
dissipation factor	δ	$\delta = \alpha_a - \tau$	1

Table 1.2 Symbols and Terminology for Physical and Chemical Quantities: Electricity and Magnetism (*From [1]. Used with permission.*)

Name	Symbol	Definition	SI unit
quantity of electricity, electric charge	Q		C
charge density	ρ	$\rho = Q/V$	C m^{-3}
surface charge density	σ	$\sigma = Q/A$	C m^{-2}
electric potential	V, ϕ	$V = dW/dQ$	V, J C^{-1}
electric potential difference	$U, \Delta V, \Delta\phi$	$U = V_2 - V_1$	V
electromotive force	E	$E = \int (\mathbf{F}/Q) \cdot d\mathbf{s}$	V
electric field strength	$\mathbf{E}$	$\mathbf{E} = \mathbf{F}/Q = -\text{grad } V$	V m^{-1}
electric flux	Ψ	$\Psi = \int \mathbf{D} \cdot d\mathbf{A}$	C
electric displacement	$\mathbf{D}$	$\mathbf{D} = \epsilon \mathbf{E}$	C m^{-2}
capacitance	C	$C = Q/U$	F, C V^{-1}
permittivity	ϵ	$\mathbf{D} = \epsilon \mathbf{E}$	F m^{-1}
permittivity of vacuum	ϵ_0	$\epsilon_0 = \mu_0^{-1} c_0^{-2}$	F m^{-1}
relative permittivity	ϵ_r	$\epsilon_r = \epsilon/\epsilon_0$	1
dielectric polarization (dipole moment per volume)	$\mathbf{P}$	$\mathbf{P} = \mathbf{D} - \epsilon_0 \mathbf{E}$	C m^{-2}
electric susceptibility	χ_e	$\chi_e = \epsilon_r - 1$	1
electric dipole moment	$\mathbf{p}, \mu$	$\mathbf{p} = Q\mathbf{r}$	C m
electric current	I	$I = dQ/dt$	A
electric current density	$\mathbf{j}, \mathbf{J}$	$I = \int \mathbf{j} \cdot d\mathbf{A}$	A m^{-2}
magnetic flux density, magnetic induction	$\mathbf{B}$	$\mathbf{F} = Q\mathbf{v} \times \mathbf{B}$	T
magnetic flux	Φ	$\Phi = \int \mathbf{B} \cdot d\mathbf{A}$	Wb
magnetic field strength	$\mathbf{H}$	$\mathbf{B} = \mu \mathbf{H}$	A m^{-1}
permeability	μ	$\mathbf{B} = \mu \mathbf{H}$	$\text{N A}^{-2}, \text{H m}^{-1}$
permeability of vacuum	μ_0		H m^{-1}
relative permeability	μ_r	$\mu_r = \mu/\mu_0$	1
magnetization (magnetic dipole moment per volume)	$\mathbf{M}$	$\mathbf{M} = \mathbf{B}/\mu_0 - \mathbf{H}$	A m^{-1}
magnetic susceptibility	$\chi, \kappa, (\chi_m)$	$\chi = \mu_r - 1$	1
molar magnetic susceptibility	χ_m	$\chi_m = V_m \chi$	$\text{m}^3 \text{mol}^{-1}$
magnetic dipole moment	$\mathbf{m}, \mu$	$E_p = -\mathbf{m} \cdot \mathbf{B}$	$\text{A m}^2, \text{J T}^{-1}$
electrical resistance	R	$R = U/I$	Ω
conductance	G	$G = 1/R$	S
loss angle	δ	$\delta = (\pi/2) + \phi_I - \phi_U$	1, rad
reactance	X	$X = (U/I) \sin \delta$	Ω
impedance (complex impedance)	Z	$Z = R + iX$	Ω
admittance (complex admittance)	Y	$Y = 1/Z$	S
susceptance	B	$Y = G + iB$	S
resistivity	ρ	$\rho = E/j$	$\Omega \text{ m}$
conductivity	κ, γ, σ	$\kappa = 1/\rho$	S m^{-1}
self-inductance	L	$E = -L(dI/dt)$	H
mutual inductance	M, L_{12}	$E_1 = L_{12}(dI_2/dt)$	H
magnetic vector potential	$\mathbf{A}$	$\mathbf{B} = \nabla \times \mathbf{A}$	Wb m^{-1}
Poynting vector	$\mathbf{S}$	$\mathbf{S} = \mathbf{E} \times \mathbf{H}$	W m^{-2}

Table 1.3 Symbols and Terminology for Physical and Chemical Quantities: Electromagnetic Radiation (*From [1]. Used with permission.*)

Name	Symbol	Definition	SI unit
wavelength	λ		m
speed of light in vacuum	c_0		m s ⁻¹
in a medium	c	$c = c_0/n$	m s ⁻¹
wavenumber in vacuum	$\tilde{\nu}$	$\tilde{\nu} = \nu/c_0 = 1/n\lambda$	m ⁻¹
wavenumber (in a medium)	σ	$\sigma = 1/\lambda$	m ⁻¹
frequency	ν	$\nu = c/\lambda$	Hz
circular frequency, pulsatance	ω	$\omega = 2\pi\nu$	s ⁻¹ , rad s ⁻¹
refractive index	n	$n = c_0/c$	1
Planck constant	h		J s
Planck constant/2 π	$\hbar$	$\hbar = h/2\pi$	J s
radiant energy	Q, W		J
radiant energy density	ρ, w	$\rho = Q/V$	J m ⁻³
spectral radiant energy density			
in terms of frequency	ρ_ν, w_ν	$\rho_\nu = d\rho/d\nu$	J m ⁻³ Hz ⁻¹
in terms of wavenumber	$\rho_{\tilde{\nu}}, w_{\tilde{\nu}}$	$\rho_{\tilde{\nu}} = d\rho/d\tilde{\nu}$	J m ⁻²
in terms of wavelength	ρ_λ, w_λ	$\rho_\lambda = d\rho/d\lambda$	J m ⁻⁴
Einstein transition probabilities			
spontaneous emission	A_{nm}	$dN_n/dt = -A_{nm}N_n$	s ⁻¹
stimulated emission	B_{nm}	$dN_n/dt = -\rho_{\tilde{\nu}}(\tilde{\nu}_{nm}) \times B_{nm}N_n$	s kg ⁻¹
stimulated absorption	B_{mn}	$dN_n/dt = \rho_{\tilde{\nu}}(\tilde{\nu}_{nm})B_{mn}N_m$	s kg ⁻¹
radiant power, radiant energy per time	Φ, P	$\Phi = dQ/dt$	W
radiant intensity	I	$I = d\Phi/d\Omega$	W sr ⁻¹
radiant exitance (emitted radiant flux)	M	$M = d\Phi/dA_{\text{source}}$	W m ⁻²
irradiance (radiant flux received)	$E, (I)$	$E = d\Phi/dA$	W m ⁻²
emittance	ε	$\varepsilon = M/M_{\text{bb}}$	1
Stefan-Boltzman constant	σ	$M_{\text{bb}} = \sigma T^4$	W m ⁻² K ⁻⁴
first radiation constant	c_1	$c_1 = 2\pi\hbar c_0^2$	W m ²
second radiation constant	c_2	$c_2 = \hbar c_0/k$	K m
transmittance, transmission factor	τ, T	$\tau = \Phi_{\text{tr}}/\Phi_0$	1
absorptance, absorption factor	α	$\alpha = \Phi_{\text{abs}}/\Phi_0$	1
reflectance, reflection factor	ρ	$\rho = \Phi_{\text{refl}}/\Phi_0$	1
(decadic) absorbance	A	$A = \lg(1 - \alpha_i)$	1
napierian absorbance	B	$B = \ln(1 - \alpha_i)$	1
absorption coefficient			
(linear) decadic	a, K	$a = A/l$	m ⁻¹
(linear) napierian	α	$\alpha = B/l$	m ⁻¹
molar (decadic)	ε	$\varepsilon = a/c = A/cl$	m ² mol ⁻¹
molar napierian	κ	$\kappa = \alpha/c = B/cl$	m ² mol ⁻¹
absorption index	k	$k = \alpha/4\pi\tilde{\nu}$	1
complex refractive index	$\hat{n}$	$\hat{n} = n + ik$	1
molar refraction	R, R_m	$R = \frac{n^2 - 1}{n^2 + 2} V_m$	m ³ mol ⁻¹
angle of optical rotation	α		1, rad

Table 1.4 Symbols and Terminology for Physical and Chemical Quantities: Solid State
(From [1]. Used with permission.)

Name	Symbol	Definition	SI unit
lattice vector	$\mathbf{R}, \mathbf{R}_0$		m
fundamental translation vectors for the crystal lattice	$\mathbf{a}_1; \mathbf{a}_2; \mathbf{a}_3,$ $\mathbf{a}; \mathbf{b}; \mathbf{c}$	$\mathbf{R} = n_1 \mathbf{a}_1 + n_2 \mathbf{a}_2 + n_3 \mathbf{a}_3$	m
(circular) reciprocal lattice vector	$\mathbf{G}$	$\mathbf{G} \cdot \mathbf{R} = 2\pi m$	m^{-1}
(circular) fundamental translation vectors for the reciprocal lattice	$\mathbf{b}_1; \mathbf{b}_2; \mathbf{b}_3,$ $\mathbf{a}^*; \mathbf{b}^*; \mathbf{c}^*$	$\mathbf{a}_i \cdot \mathbf{b}_k = 2\pi \delta_{ik}$	m^{-1}
lattice plane spacing	d		m
Bragg angle	θ	$n\lambda = 2d \sin \theta$	1, rad
order of reflection	n		1
order parameters			
short range	σ		1
long range	s		1
Burgers vector	$\mathbf{b}$		m
particle position vector	$\mathbf{r}, \mathbf{R}_j$		m
equilibrium position	$\mathbf{R}_0$		m
vector of an ion			
equilibrium position	$\mathbf{R}_0$		m
vector of an ion			
displacement vector of an ion	$\mathbf{u}$	$\mathbf{u} = \mathbf{R} - \mathbf{R}_0$	m
Debye–Waller factor	B, D		1
Debye circular wavenumber	q_D		m^{-1}
Debye circular frequency	ω_D		s^{-1}
Grüneisen parameter	γ, Γ	$\gamma = \alpha V / \kappa C_V$	1
Madelung constant	$\alpha, \mathcal{M}$	$E_{\text{coul}} = \frac{\alpha N_A z_+ z_- e^2}{4\pi \epsilon_0 R_0}$	1
density of states	N_E	$N_E = dN(E)/dE$	$\text{J}^{-1} \text{m}^{-3}$
(spectral) density of vibrational modes	N_ω, g	$N_\omega = dN(\omega)/d\omega$	s m^{-3}
resistivity tensor	ρ_{ik}	$E = \rho \cdot \mathbf{j}$	$\Omega \text{ m}$
conductivity tensor	σ_{ik}	$\sigma = \rho^{-1}$	S m^{-1}
thermal conductivity tensor	λ_{ik}	$J_q = -\lambda \cdot \text{grad } T$	$\text{W m}^{-1} \text{K}^{-1}$
residual resistivity	ρ_R		$\Omega \text{ m}$
relaxation time	τ	$\tau = l/v_F$	s
Lorenz coefficient	L	$L = \lambda/\sigma T$	$\text{V}^2 \text{K}^{-2}$
Hall coefficient	A_H, R_H	$E = \rho \cdot \mathbf{j} + R_H (\mathbf{B} \times \mathbf{j})$	$\text{m}^3 \text{C}^{-1}$
thermoelectric force	E		V
Peltier coefficient	Π		V
Thomson coefficient	$\mu, (\tau)$		V K^{-1}
work function	Φ	$\Phi = E_\infty - E_F$	J
number density,	$n, (p)$		m^{-3}
number concentration			
gap energy	E_g		J
donor ionization energy	E_d		J
acceptor ionization energy	E_a		J
Fermi energy	E_F, ϵ_F		J
circular wave vector,	$\mathbf{k}, \mathbf{q}$	$k = 2\pi/\lambda$	m^{-1}
propagation vector			
Bloch function	$u_k(\mathbf{r})$	$\psi(\mathbf{r}) = u_k(\mathbf{r}) \exp(i\mathbf{k} \cdot \mathbf{r})$	$\text{m}^{-3/2}$
charge density of electrons	ρ	$\rho(\mathbf{r}) = -e\psi^*(\mathbf{r})\psi(\mathbf{r})$	C m^{-3}
effective mass	m^*		kg
mobility	μ	$\mu = v_{\text{drift}}/E$	$\text{m}^2 \text{V}^{-1} \text{s}^{-1}$
mobility ratio	b	$b = \mu_n/\mu_p$	1
diffusion coefficient	D	$dN/dt = -DA(dn/dx)$	$\text{m}^2 \text{s}^{-1}$
diffusion length	L	$L = \sqrt{D\tau}$	m
characteristic (Weiss)	ϕ, ϕ_W		K
temperature			
Curie temperature	T_C		K
Néel temperature	T_N		K

Table 1.5 Total Elongation at Failure of Selected Polymers (*From [1]. Used with permission.*)

Polymer	Elongation
ABS	5–20
Acrylic	2–7
Epoxy	4.4
HDPE	700–1000
Nylon, type 6	30–100
Nylon 6/6	15–300
Phenolic	0.4–0.8
Polyacetal	25
Polycarbonate	110
Polyester	300
Polypropylene	100–600
PTFE	250–350

Table 1.6 Tensile Strength of Selected Wrought Aluminum Alloys (*From [1]. Used with permission.*)

Alloy	Temper	TS (MPa)
1050	0	76
1050	H16	130
2024	0	185
2024	T361	495
3003	0	110
3003	H16	180
5050	0	145
5050	H34	195
6061	0	125
6061	T6, T651	310
7075	0	230
7075	T6, T651	570

Table 1.7 Density of Selected Materials, Mg/m³ (*From [1]. Used with permission.*)

Metal		Ceramic		Glass		Polymer	
Ag	10.50	Al ₂ O ₃	3.97–3.986	SiO ₂	2.20	ABS	1.05–1.07
Al	2.7	BN (cub)	3.49	SiO ₂ 10 wt% Na ₂ O	2.291	Acrylic	1.17–1.19
Au	19.28	BeO	3.01–3.03	SiO ₂ 19.55 wt% Na ₂ O	2.383	Epoxy	1.80–2.00
Co	8.8	MgO	3.581	SiO ₂ 29.20 wt% Na ₂ O	2.459	HDPE	0.96
Cr	7.19	SiC(hex)	3.217	SiO ₂ 39.66 wt% Na ₂ O	2.521	Nylon, type 6	1.12–1.14
Cu	8.93	Si ₃ N ₄ (α)	3.184	SiO ₂ 39.0 wt% CaO	2.746	Nylon 6/6	1.13–1.15
Fe	7.87	Si ₃ N ₄ (β)	3.187			Phenolic	1.32–1.46
Ni	8.91	TiO ₂ (rutile)	4.25			Polyacetal	1.425
Pb	11.34	UO ₂	10.949–10.97			Polycarbonate	1.2
Pt	21.44	ZrO ₂ (CaO)	5.5			Polyester	1.31
Ti	4.51	Al ₂ O ₃ MgO	3.580			Polystyrene	1.04
W	19.25	3Al ₂ O ₃ 2SiO ₂	2.6–3.26			PTFE	2.1–2.3

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Table 1.8 Dielectric Constants of Ceramics (*From [1]. Used with permission.*)

Material	Dielectric constant, 10^6 Hz	Dielectric strength V/mil	Volume resistivity $\Omega \cdot \text{cm}$ (23°C)	Loss factor ^a
Alumina	4.5–8.4	40–160	10^{11} – 10^{14}	0.0002–0.01
Corderite	4.5–5.4	40–250	10^{12} – 10^{14}	0.004–0.012
Forsterite	6.2	240	10^{14}	0.0004
Porcelain (dry process)	6.0–8.0	40–240	10^{12} – 10^{14}	0.0003–0.02
Porcelain (wet process)	6.0–7.0	90–400	10^{12} – 10^{14}	0.006–0.01
Porcelain, zircon	7.1–10.5	250–400	10^{13} – 10^{15}	0.0002–0.008
Steatite	5.5–7.5	200–400	10^{13} – 10^{15}	0.0002–0.004
Titanates (Ba, Sr, Ca, Mg, and Pb)	15–12.000	50–300	10^8 – 10^{15}	0.0001–0.02
Titanium dioxide	14–110	100–210	10^{13} – 10^{18}	0.0002–0.005

^aPower factor $\times$ dielectric constant equals loss factor.

Table 1.9 Dielectric Constants of Glass (*From [1]. Used with permission.*)

Type	Dielectric constant at 100 MHz (20°C)	Volume resistivity (350°C M $\Omega \cdot \text{cm}$)	Loss factor ^a
Corning 0010	6.32	10	0.015
Corning 0080	6.75	0.13	0.058
Corning 0120	6.65	100	0.012
Pyrex 1710	6.00	2,500	0.025
Pyrex 3320	4.71	–	0.019
Pyrex 7040	4.65	80	0.013
Pyrex 7050	4.77	16	0.017
Pyrex 7052	5.07	25	0.019
Pyrex 7060	4.70	13	0.018
Pyrex 7070	4.00	1,300	0.0048
Vycor 7230	3.83	–	0.0061
Pyrex 7720	4.50	16	0.014
Pyrex 7740	5.00	4	0.040
Pyrex 7750	4.28	50	0.011
Pyrex 7760	4.50	50	0.0081
Vycor 7900	3.9	130	0.0023
Vycor 7910	3.8	1,600	0.00091
Vycor 7911	3.8	4,000	0.00072
Corning 8870	9.5	5,000	0.0085
G.E. Clear (silica glass)	3.81	4,000–30,000	0.00038
Quartz (fused)	3.75–4.1 (1 MHz)	–	0.0002 1 MHz

^aPower factor $\times$ dielectric constant equals loss factor.

Table 1.10 Dielectric Constants of Solids in the Temperature Range 17–22°C (*From* [1]. *Used with permission.*)

Material	Freq., Hz	Dielectric constant	Material	Freq., Hz	Dielectric Constant
Acetamide	4×10^8	4.0	Phenanthrene	4×10^8	2.80
Acetanilide	—	2.9	Phenol (10°C)	4×10^8	4.3
Acetic acid (2°C)	4×10^8	4.1	Phosphorus, red	10^8	4.1
Aluminum oleate	4×10^8	2.40	Phosphorus, yellow	10^8	3.6
Ammonium bromide	10^8	7.1	Potassium aluminum sulfate	10^6	3.8
Ammonium chloride	10^8	7.0	Potassium carbonate (15°C)	10^8	5.6
Antimony trichloride	10^8	5.34	Potassium chlorate	6×10^7	5.1
Apatite $\perp$ optic axis	3×10^8	9.50	Potassium chloride	10^4	5.03
Apatite $\parallel$ optic axis	3×10^8	7.41	Potassium chromate	6×10^7	7.3
Asphalt	$<3 \times 10^6$	2.68	Potassium iodide	6×10^7	5.6
Barium chloride (anhyd.)	6×10^7	11.4	Potassium nitrate	6×10^7	5.0
Barium chloride (2H ₂ O)	6×10^7	9.4	Potassium sulfate	6×10^7	5.9
Barium nitrate	6×10^7	5.9	Quartz $\perp$ optic axis	3×10^7	4.34
Barium sulfate (15°C)	10^8	11.4	Quartz $\parallel$ optic axis	3×10^7	4.27
Beryl $\perp$ optic axis	10^4	7.02	Resorcinol	4×10^8	3.2
Beryl $\parallel$ optic axis	10^4	6.08	Ruby $\perp$ optic axis	10^4	13.27
Calcite $\perp$ optic axis	10^4	8.5	Ruby $\parallel$ optic axis	10^4	11.28
Calcite $\parallel$ optic axis	10^4	8.0	Rutile $\perp$ optic axis	10^8	86
Calcium carbonate	10^6	6.14	Rutile $\parallel$ optic axis	10^8	170
Calcium fluoride	10^4	7.36	Selenium	10^8	6.6
Calcium sulfate (2H ₂ O)	10^4	5.66	Silver bromide	10^6	12.2
Cassiterite $\perp$ optic axis	10^{12}	23.4	Silver chloride	10^6	11.2
Cassiterite $\parallel$ optic axis	10^{12}	24	Silver cyanide	10^6	5.6
d-Cocaine	5×10^8	3.10	Smithsonite $\perp$ optic axis	10^{12}	9.3
Cupric oleate	4×10^8	2.80	Smithsonite $\parallel$ optic axis	10^{10}	9.4
Cupric oxide (15°C)	10^8	18.1	Sodium carbonate (anhyd.)	6×10^7	8.4
Cupric sulfate (anhyd.)	6×10^7	10.3	Sodium carbonate (10H ₂ O)	6×10^7	5.3
Cupric sulfate (5H ₂ O)	6×10^7	7.8	Sodium chloride	10^4	6.12
Diamond	10^8	5.5	Sodium nitrate	—	5.2
Diphenylmethane	4×10^8	2.7	Sodium oleate	4×10^8	2.75
Dolomite $\perp$ optic axis	10^8	8.0	Sodium perchlorate	6×10^7	5.4
Dolomite $\parallel$ optic axis	10^8	6.8	Sucrose (mean)	3×10^8	3.32
Ferrous oxide (15°C)	10^8	14.2	Sulfur (mean)	—	4.0
Iodine	10^8	4	Thallium chloride	10^6	46.9
Lead acetate	10^6	2.6	p-Toluidine	4×10^8	3.0
Lead carbonate (15°C)	10^8	18.6	Tourmaline $\perp$ optic axis	10^4	7.10
Lead chloride	10^6	4.2	Tourmaline $\parallel$ optic axis	10^4	6.3
Lead monoxide (15°C)	10^8	25.9	Urea	4×10^8	3.5
Lead nitrate	6×10^7	37.7	Zircon $\perp$, $\parallel$	10^8	12
Lead oleate	4×10^8	3.27			
Lead sulfate	10^6	14.3			
Lead sulfide (15°)	10^6	17.9			
Malachite (mean)	10^{12}	7.2			
Mercuric chloride	10^6	3.2			
Mercurous chloride	10^6	9.4			
Naphthalene	4×10^8	2.52			

Whitaker, Jerry C. "International Standards and Constants"
The Resource Handbook of Electronics.
Ed. Jerry C. Whitaker
Boca Raton: CRC Press LLC, ©2001

International Standards and Constants

2.1 Introduction

Standardization usually starts within a company as a way to reduce costs associated with parts stocking, design drawings, training, and retraining of personnel. The next level might be a cooperative agreement between firms making similar equipment to use standardized dimensions, parts, and components. Competition, trade secrets, and the *NIH factor* (not invented here) often generate an atmosphere that prevents such an understanding. Enter the professional engineering society, which promises a forum for discussion between users and engineers while downplaying the commercial and business aspects.

2.2 The History of Modern Standards

In 1836, the U.S. Congress authorized the Office of Weights and Measures (OWM) for the primary purpose of ensuring uniformity in custom house dealings. The Treasury Department was charged with its operation. As advancements in science and technology fueled the industrial revolution, it was apparent that standardization of hardware and test methods was necessary to promote commercial development and to compete successfully with the rest of the world. The industrial revolution in the 1830s introduced the need for interchangeable parts and hardware. Economical manufacture of transportation equipment, tools, weapons, and other machinery was possible only with mechanical standardization.

By the late 1800s professional organizations of mechanical, electrical, chemical, and other engineers were founded with this aim in mind. The Institute of Electrical Engineers developed standards between 1890 and 1910 based on the practices of the major electrical manufacturers of the time. Such activities were not within the purview of the OWM, so there was no government involvement during this period. It took the pressures of war production in 1918 to cause the formation of the American Engineering

Standards Committee (AESC) to coordinate the activities of various industry and engineering societies. This group became the American Standards Association (ASA) in 1928.

Parallel developments would occur worldwide. The International Bureau of Weights and Measures was founded in 1875, the International Electrotechnical Commission (IEC) in 1904, and the International Federation of Standardizing Bodies (ISA) in 1926. Following World War II (1946) this group was reorganized as the International Standards Organization (ISO) comprised of the ASA and the standardizing bodies of 25 other countries. Present participation is approximately 55 countries and 145 technical committees. The stated mission of the ISO is *to facilitate the internationalization and unification of industrial standards*.

The International Telecommunications Union (ITU) was founded in 1865 for the purpose of coordinating and interfacing telegraphic communications worldwide. Today, its member countries develop regulations and voluntary recommendations, and provide coordination of telecommunications development. A sub-group, the International Radio Consultative Committee (CCIR) (which no longer exists under this name), is concerned with certain transmission standards and the compatible use of the frequency spectrum, including geostationary satellite orbit assignments. Standardized transmission formats to allow interchange of communications over national boundaries are the purview of this committee. Because these standards involve international treaties, negotiations are channeled through the U.S. State Department.

2.2.1 American National Standards Institute (ANSI)

ANSI coordinates policies to promote procedures, guidelines, and the consistency of standards development. Due process procedures ensure that participation is open to all persons who are materially affected by the activities without domination by a particular group. Written procedures are available to ensure that consistent methods are used for standards developments and appeals. Today, there are more than 1000 members who support the U.S. voluntary standardization system as members of the ANSI federation. This support keeps the Institute financially sound and the system free of government control.

The functions of ANSI include: (1) serving as a clearinghouse on standards development and supplying standards-related publications and information, and (2) the following business development issues:

- Provides national and international standards information necessary to market products worldwide.
- Offers American National Standards that assist companies in reducing operating and purchasing costs, thereby assuring product quality and safety.
- Offers an opportunity to voice opinion through representation on numerous technical advisory groups, councils, and boards.
- Furnishes national and international recognition of standards for credibility and force in domestic commerce and world trade.

- Provides a path to influence and comment on the development of standards in the international arena.

Prospective standards must be submitted by an ANSI accredited standards developer. There are three methods which may be used:

- **Accredited organization method.** This approach is most often used by associations and societies having an interest in developing standards. Participation is open to all interested parties as well as members of the association or society. The standards developer must fashion its own operating procedures, which must meet the general requirements of the ANSI procedures.
- **Accredited standards committee method.** Standing committees of directly and materially affected interests develop documents and establish consensus in support of the document. This method is most often used when a standard affects a broad range of diverse interests or where multiple associations or societies with similar interests exist. These committees are administered by a *secretariat*, an organization that assumes the responsibility for providing compliance with the pertinent operating procedures. The committee can develop its own operating procedures consistent with ANSI requirements, or it can adopt standard ANSI procedures.
- **Accredited canvass method.** This approach is used by smaller trade associations or societies that have documented current industry practices and desire that these standards be recognized nationally. Generally, these developers are responsible for less than five standards. The developer identifies those who are directly and materially affected by the activity in question and conducts a letter ballot *canvass* of those interests to determine consensus. Developers must use standard ANSI procedures.

Note that all methods must fulfill the basic requirements of public review, voting, consideration, and disposition of all views and objections, and an appeals mechanism.

The introduction of new technologies or changes in the direction of industry groups or engineering societies may require a mediating body to assign responsibility for a developing standard to the proper group. The Joint Committee for Intersociety Coordination (JCIC) operates under ANSI to fulfill this need.

2.2.2 Professional Society Engineering Committees

The engineering groups that collate and coordinate activities that are eventually presented to standardization bodies encourage participation from all concerned parties. Meetings are often scheduled in connection with technical conferences to promote greater participation. Other necessary meetings are usually scheduled in geographical locations of the greatest activity in the field. There are no charges or dues to be a member or to attend the meetings. An interest in these activities can still be served by reading the reports from these groups in the appropriate professional journals. These

wheels may seem to grind exceedingly slowly at times, but the adoption of standards that may have to endure for 50 years or more should not be taken lightly.

2.3 References

1. Whitaker, Jerry C. (ed.), *The Electronics Handbook*, CRC Press, Boca Raton, FL, 1996.

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Whitaker, Jerry C., and K. Blair Benson (eds.), *Standard Handbook of Video and Television Engineering*, McGraw-Hill, New York, NY, 2000.

2.5 Tabular Data

Table 2.1 Common Standard Units

Name	Symbol	Quantity
ampere	A	electric current
ampere per meter	A/m	magnetic field strength
ampere per square meter	A/m ²	current density
becquerel	Bq	activity (of a radionuclide)
candela	cd	luminous intensity
coulomb	C	electric charge
coulomb per kilogram	C/kg	exposure (x and gamma rays)
coulomb per sq. meter	C/m ²	electric flux density
cubic meter	m ³	volume
cubic meter per kilogram	m ³ /kg	specific volume
degree Celsius	°C	Celsius temperature
farad	F	capacitance
farad per meter	F/m	permittivity
henry	H	inductance
henry per meter	H/m	permeability
hertz	Hz	frequency
joule	J	energy, work, quantity of heat
joule per cubic meter	J/m ³	energy density
joule per kelvin	J/K	heat capacity
joule per kilogram K	J/(kg•K)	specific heat capacity
joule per mole	J/mol	molar energy
kelvin	K	thermodynamic temperature
kilogram	kg	mass
kilogram per cubic meter	kg/m ³	density, mass density
lumen	lm	luminous flux
lux	lx	luminance

Table 2.1 Common Standard Units (continued)

Name	Symbol	Quantity
meter	m	length
meter per second	m/s	speed, velocity
meter per second sq.	m/s ²	acceleration
mole	mol	amount of substance
newton	N	force
newton per meter	N/m	surface tension
ohm	Ω	electrical resistance
pascal	Pa	pressure, stress
pascal second	Pa•s	dynamic viscosity
radian	rad	plane angle
radian per second	rad/s	angular velocity
radian per second squared	rad/s ²	angular acceleration
second	s	time
siemens	S	electrical conductance
square meter	m ²	area
steradian	sr	solid angle
tesla	T	magnetic flux density
volt	V	electrical potential
volt per meter	V/m	electric field strength
watt	W	power, radiant flux
watt per meter kelvin	W/(m•K)	thermal conductivity
watt per square meter	W/m ²	heat (power) flux density
weber	Wb	magnetic flux

Table 2.2 Standard Prefixes

Multiple	Prefix	Symbol
10 ¹⁸	exa	E
10 ¹⁵	peta	P
10 ¹²	tera	T
10 ⁹	giga	G
10 ⁶	mega	M
10 ³	kilo	k
10 ²	hecto	h
10	deka	da
10 ⁻¹	deci	d
10 ⁻²	centi	c
10 ⁻³	milli	m
10 ⁻⁶	micro	μ
10 ⁻⁹	nano	n
10 ⁻¹²	pico	p
10 ⁻¹⁵	femto	f
10 ⁻¹⁸	atto	a

Table 2.3 Common Standard Units for Electrical Work

Unit	Symbol
centimeter	cm
cubic centimeter	cm ³
cubic meter per second	m ³ /s
gigahertz	GHz
gram	g
kilohertz	kHz
kilohm	kΩ
kilojoule	kJ
kilometer	km
kilovolt	kV
kilovoltampere	kVA
kilowatt	kW
megahertz	MHz
megavolt	MV
megawatt	MW
megohm	MΩ
microampere	μA
microfarad	μF
microgram	μg
microhenry	μH
microsecond	μs
microwatt	μW
milliampere	mA
milligram	mg
millihenry	mH
millimeter	mm
millisecond	ms
millivolt	mV
milliwatt	mW
nanoampere	nA
nanofarad	nF
nanometer	nm
nanosecond	ns
nanowatt	nW
picoampere	pA
picofarad	pF
picosecond	ps
picowatt	pW

Table 2.4 Names and Symbols for the SI Base Units (*From [1]. Used with permission.*)

Physical quantity	Name of SI unit	Symbol for SI unit
length	meter	m
mass	kilogram	kg
time	second	s
electric current	ampere	A
thermodynamic temperature	kelvin	K
amount of substance	mole	mol
luminous intensity	candela	cd

Table 2.5 Units in Use Together with the SI (These units are not part of the SI, but it is recognized that they will continue to be used in appropriate contexts. *From* [1]. *Used* with permission.)

Physical quantity	Name of unit	Symbol for unit	Value in SI units
time	minute	min	60 s
time	hour	h	3600 s
time	day	d	86 400 s
plane angle	degree	°	$(\pi/180)$ rad
plane angle	minute	'	$(\pi/10\,800)$ rad
plane angle	second	"	$(\pi/648\,000)$ rad
length	ångström ^a	Å	10^{-10} m
area	barn	b	10^{-28} m ²
volume	litre	l, L	dm ³ = 10^{-3} m ³
mass	tonne	t	Mg = 10^3 kg
pressure	bar ^a	bar	10^5 Pa = 10^5 N m ⁻²
energy	electronvolt ^b	eV (= $e \times V$)	$\approx 1.60218 \times 10^{-19}$ J
mass	unified atomic mass unit ^{b,c}	u (= $m_a(^{12}\text{C})/12$)	$\approx 1.66054 \times 10^{-27}$ kg

^aThe ångström and the bar are approved by CIPM for temporary use with SI units, until CIPM makes a further recommendation. However, they should not be introduced where they are not used at present.

^bThe values of these units in terms of the corresponding SI units are not exact, since they depend on the values of the physical constants e (for the electronvolt) and N_A (for the unified atomic mass unit), which are determined by experiment.

^cThe unified atomic mass unit is also sometimes called the dalton, with symbol Da, although the name and symbol have not been approved by CGPM.

Table 2.6 Derived Units with Special Names and Symbols (*From [1]. Used with permission.*)

Physical quantity	Name of SI unit	Symbol for SI unit	Expression in terms of SI base units
frequency ^a	hertz	Hz	s^{-1}
force	newton	N	$m\ kg\ s^{-2}$
pressure, stress	pascal	Pa	$N\ m^{-2} = m^{-1}\ kg\ s^{-2}$
energy, work, heat	joule	J	$N\ m = m^2\ kg\ s^{-2}$
power, radiant flux	watt	W	$J\ s^{-1} = m^2\ kg\ s^{-3}$
electric charge	coulomb	C	A s
electric potential, electromotive force	volt	V	$J\ C^{-1} = m^2\ kg\ s^{-3}\ A^{-1}$
electric resistance	ohm	Ω	$V\ A^{-1} = m^2\ kg\ s^{-3}\ A^{-2}$
electric conductance	siemens	S	$\Omega^{-1} = m^{-2}\ kg^{-1}\ s^3\ A^2$
electric capacitance	farad	F	$C\ V^{-1} = m^{-2}\ kg^{-1}\ s^4\ A^2$
magnetic flux density	tesla	T	$V\ s\ m^{-2} = kg\ s^{-2}\ A^{-1}$
magnetic flux	weber	Wb	$V\ s = m^2\ kg\ s^{-2}\ A^{-1}$
inductance	henry	H	$V\ A^{-1}\ s = m^2\ kg\ s^{-2}\ A^{-2}$
Celsius temperature ^b	degree Celsius	$^{\circ}C$	K
luminous flux	lumen	lm	cd sr
illuminance	lux	lx	cd sr m^{-2}
activity (radioactive)	becquerel	Bq	s^{-1}
absorbed dose (of radiation)	gray	Gy	$J\ kg^{-1} = m^2\ s^{-2}$
dose equivalent (dose equivalent index)	sievert	Sv	$J\ kg^{-1} = m^2\ s^{-2}$
plane angle	radian	rad	$1 = m\ m^{-1}$
solid angle	steradian	sr	$1 = m^2\ m^{-2}$

^aFor radial (circular) frequency and for angular velocity the unit $rad\ s^{-1}$, or simply s^{-1} , should be used, and this may not be simplified to Hz. The unit Hz should be used only for frequency in the sense of cycles per second.

^bThe Celsius temperature θ is defined by the equation:

$$\theta/^{\circ}C = T/K - 273.15$$

The SI unit of Celsius temperature interval is the degree Celsius, $^{\circ}C$, which is equal to the kelvin, K. $^{\circ}C$ should be treated as a single symbol, with no space between the $^{\circ}$ sign and the letter C. (The symbol $^{\circ}K$ and the symbol $^{\circ}$ should no longer be used.)

Table 2.7 The Greek Alphabet (*From [1]. Used with permission.*)

	Greek letter	Greek name	English equivalent		Greek letter	Greek name	English equivalent
A	α	Alpha	a	N	ν	Nu	n
B	β	Beta	b	Ξ	ξ	Xi	x
Γ	γ	Gamma	g	Ο	$\omicron$	Omicron	ö
Δ	δ	Delta	d	Π	π	Pi	p
E	ϵ	Epsilon	ě	Ρ	ρ	Rho	r
Z	ζ	Zeta	z	Σ	σ ς	Sigma	s
H	η	Eta	ê	Τ	τ	Tau	t
Θ	θ ϑ	Theta	th	Υ	υ	Upsilon	u
I	ι	Iota	i	Φ	ϕ φ	Phi	ph
K	κ	Kappa	k	Χ	χ	Chi	ch
Λ	λ	Lambda	l	Ψ	ψ	Psi	ps
M	μ	Mu	m	Ω	ω	Omega	ō

Table 2.8 Constants (*From [1]. Used with permission.*)

π Constants										
π	=	3.14159	26535	89793	23846	26433	83279	50288	41971	69399 37511
$1/\pi$	=	0.31830	98861	83790	67153	77675	26745	02872	40689	19291 48091
π^2	=	9.8690	44010	89358	61883	44909	99876	15113	53136	99407 24079
$\log_e \pi$	=	1.14472	98858	49400	17414	34273	51353	05871	16472	94812 91531
$\log_{10} \pi$	=	0.49714	98726	94133	85435	12682	88290	89887	36516	78324 38044
$\log_{10} \sqrt{2}\pi$	=	0.39908	99341	79057	52478	25035	91507	69595	02099	34102 92128
Constants Involving e										
e	=	2.71828	18284	59045	23536	02874	71352	66249	77572	47093 69996
$1/e$	=	0.36787	94411	71442	32159	55237	70161	46086	74458	11131 03177
e^2	=	7.38905	60989	30650	22723	04274	60575	00781	31803	15570 55185
$M = \log_{10} e$	=	0.43429	44819	03251	82765	11289	18916	60508	22943	97005 80367
$1/M = \log_e 10$	=	2.30258	50929	94045	68401	79914	54684	36420	76011	01488 62877
$\log_{10} M$	=	9.63778	43113	00536	78912	29674	98645	—10		
Numerical Constants										
$\sqrt{2}$	=	1.41421	35623	73095	04880	16887	24209	69807	85696	71875 37695
$\sqrt[3]{2}$	=	1.25992	10498	94873	16476	72106	07278	22835	05702	51464 70151
$\log_e 2$	=	0.69314	71805	59945	30941	72321	21458	17656	80755	00134 36026
$\log_{10} 2$	=	0.30102	99956	63981	19521	37388	94724	49302	67881	89881 46211
$\sqrt{3}$	=	1.73205	08075	68877	29352	74463	41505	87236	69428	05253 81039
$\sqrt[3]{3}$	=	1.44224	95703	07408	38232	16383	10780	10958	83918	69253 49935
$\log_e 3$	=	1.09861	22886	68109	69139	52452	36922	52570	46474	90557 82275
$\log_{10} 3$	=	0.47712	12547	19662	43729	50279	03255	11530	92001	28864 19070

Whitaker, Jerry C. "Electromagnetic Spectrum"
The Resource Handbook of Electronics.
Ed. Jerry C. Whitaker
Boca Raton: CRC Press LLC, ©2001

Electromagnetic Spectrum

3.1 Introduction

The usable spectrum of electromagnetic-radiation frequencies extends over a range from below 100 Hz for power distribution to 10²⁰ for the shortest X-rays. The lower frequencies are used primarily for terrestrial broadcasting and communications. The higher frequencies include visible and near-visible infrared and ultraviolet light, and X-rays.

3.1.1 Operating Frequency Bands

The standard frequency band designations are listed in [Tables 3.1](#) and [3.2](#). Alternate and more detailed subdivision of the VHF, UHF, SHF, and EHF bands are given in [Tables 3.3](#) and [3.4](#).

Low-End Spectrum Frequencies (1 to 1000 Hz)

Electric power is transmitted by wire but not by radiation at 50 and 60 Hz, and in some limited areas, at 25 Hz. Aircraft use 400-Hz power in order to reduce the weight of iron in generators and transformers. The restricted bandwidth that would be available for communication channels is generally inadequate for voice or data transmission, although some use has been made of communication over power distribution circuits using modulated carrier frequencies.

Low-End Radio Frequencies (1000 to 100 kHz)

These low frequencies are used for very long distance radio-telegraphic communication where extreme reliability is required and where high-power and long antennas can be erected. The primary bands of interest for radio communications are given in [Table 3.5](#).

Table 3.1 Standardized Frequency Bands (*From [1]. Used with permission.*)

Extremely low-frequency (ELF) band:	30 Hz up to 300 Hz	(10 Mm down to 1 Mm)
Voice-frequency (VF) band:	300 Hz up to 3 kHz	(1 Mm down to 100 km)
Very low-frequency (VLF) band:	3 kHz up to 30 kHz	(100 km down to 10 km)
Low-frequency (LF) band:	30 kHz up to 300 kHz	(10 km down to 1 km)
Medium-frequency (MF) band:	300 kHz up to 3 MHz	(1 km down to 100 m)
High-frequency (HF) band:	3 MHz up to 30 MHz	(100 m down to 10 m)
Very high-frequency (VHF) band:	30 MHz up to 300 MHz	(10 m down to 1 m)
Ultra high-frequency (UHF) band:	300 MHz up to 3 GHz	(1 m down to 10 cm)
Super high-frequency (SHF) band:	3 GHz up to 30 GHz	(1 cm down to 1 cm)
Extremely high-frequency (EHF) band:	30 GHz up to 300 GHz	(1 cm down to 1 mm)

Table 3.2 Standardized Frequency Bands at 1GHz and Above (*From [1]. Used with permission.*)

L band:	1 GHz up to 2 GHz	(30 cm down to 15 cm)
S band:	2 GHz up to 4 GHz	(15 cm down to 7.5 cm)
C band:	4 GHz up to 8 GHz	(7.5 cm down to 3.75 cm)
X band:	8 GHz up to 12 GHz	(3.75 cm down to 2.5 cm)
Ku band:	12 GHz up to 18 GHz	(2.5 cm down to 1.67 cm)
K band:	18 GHz up to 26.5 GHz	(1.67 cm down to 1.13 cm)
Ka band:	26.5 GHz up to 40 GHz	(1.13 cm down to 7.5 mm)
Q band:	32 GHz up to 50 GHz	(9.38 mm down to 6 mm)
U band:	40 GHz up to 60 GHz	(7.5 mm down to 5 mm)
V band:	50 GHz up to 75 GHz	(6 mm down to 4 mm)
W band:	75 GHz up to 100 GHz	(4 mm down to 3.33 mm)

Medium-Frequency Radio (20 kHz to 2 MHz)

The low-frequency portion of the band is used for around-the-clock communication services over moderately long distances and where adequate power is available to overcome the high level of atmospheric noise. The upper portion is used for AM radio, although the strong and quite variable *sky wave* occurring during the night results in substandard quality and severe fading at times. The greatest use is for AM broadcasting, in addition to fixed and mobile service, LORAN ship and aircraft navigation, and amateur radio communication.

High-Frequency Radio (2 to 30 MHz)

This band provides reliable medium-range coverage during daylight and, when the transmission path is in total darkness, worldwide long-distance service, although the

Table 3.3 Detailed Subdivision of the UHF, SHF, and EHF Bands (*From [1]. Used with permission.*)

L band:	1.12 GHz up to 1.7 GHz	(26.8 cm down to 17.6 cm)
LS band:	1.7 GHz up to 2.6 GHz	(17.6 cm down to 11.5 cm)
S band:	2.6 GHz up to 3.95 GHz	(11.5 cm down to 7.59 cm)
C(G) band:	3.95 GHz up to 5.85 GHz	(7.59 cm down to 5.13 cm)
XN(J, XC) band:	5.85 GHz up to 8.2 GHz	(5.13 cm down to 3.66 cm)
XB(H, BL) band:	7.05 GHz up to 10 GHz	(4.26 cm down to 3 cm)
X band:	8.2 GHz up to 12.4 GHz	(3.66 cm down to 2.42 cm)
Ku(P) band:	12.4 GHz up to 18 GHz	(2.42 cm down to 1.67 cm)
K band:	18 GHz up to 26.5 GHz	(1.67 cm down to 1.13 cm)
V(R, Ka) band:	26.5 GHz up to 40 GHz	(1.13 cm down to 7.5 mm)
Q(V) band:	33 GHz up to 50 GHz	(9.09 mm down to 6 mm)
M(W) band:	50 GHz up to 75 GHz	(6 mm down to 4 mm)
E(Y) band:	60 GHz up to 90 GHz	(5 mm down to 3.33 mm)
F(N) band:	90 GHz up to 140 GHz	(3.33 mm down to 2.14 mm)
G(A) band:	140 GHz up to 220 GHz	(2.14 mm down to 1.36 mm)
R band:	220 GHz up to 325 GHz	(1.36 mm down to 0.923 mm)

Table 3.4 Subdivision of the VHF, UHF, SHF Lower Part of the EHF Band (*From [1]. Used with permission.*)

A band:	100 MHz up to 250 MHz	(3 m down to 1.2 m)
B band:	250 MHz up to 500 MHz	(1.2 m down to 60 cm)
C band:	500 MHz up to 1 GHz	(60 cm down to 30 cm)
D band:	1 GHz up to 2 GHz	(30 cm down to 15 cm)
E band:	2 GHz up to 3 GHz	(15 cm down to 10 cm)
F band:	3 GHz up to 4 GHz	(10 cm down to 7.5 cm)
G band:	4 GHz up to 6 GHz	(7.5 cm down to 5 cm)
H band:	6 GHz up to 8 GHz	(5 cm down to 3.75 cm)
I band:	8 GHz up to 10 GHz	(3.75 cm down to 3 cm)
J band:	10 GHz up to 20 GHz	(3 cm down to 1.5 cm)
K band:	20 GHz up to 40 GHz	(1.5 cm down to 7.5 mm)
L band:	40 GHz up to 60 GHz	(7.5 mm down to 5 mm)
M band:	60 GHz up to 100 GHz	(5 mm down to 3 mm)

reliability and signal quality of the latter is dependent to a large degree upon ionospheric conditions and related long-term variations in sun-spot activity affecting sky-wave propagation. The primary applications include broadcasting, fixed and mobile services, telemetering, and amateur transmissions.

Table 3.5 Radio Frequency Bands (*From [1]. Used with permission.*)

Longwave broadcasting band:	150–290 kHz
AM broadcasting band:	550–1640 kHz (1.640 MHz) (107 Channels, 10-kHz separation)
International broadcasting band:	3–30 MHz
Shortwave broadcasting band:	5.95–26.1 MHz (8 bands)
VHF television (channels 2–4):	54–72 MHz
VHF television (channels 5–6):	76–88 MHz
FM broadcasting band:	88–108 MHz
VHF television (channels 7–13):	174–216 MHz
UHF television (channels 14–83):	470–890 MHz

Very High and Ultrahigh Frequencies (30 MHz to 3 GHz)

VHF and UHF bands, because of the greater channel bandwidth possible, can provide transmission of a large amount of information, either as television detail or data communication. Furthermore, the shorter wavelengths permit the use of highly directional parabolic or multielement antennas. Reliable long-distance communication is provided using high-power *tropospheric scatter* techniques. The multitude of uses include, in addition to television, fixed and mobile communication services, amateur radio, radio astronomy, satellite communication, telemetering, and radar.

Microwaves (3 to 300 GHz)

At these frequencies, many transmission characteristics are similar to those used for shorter optical waves, which limit the distances covered to line of sight. Typical uses include television relay, satellite, radar, and wide-band information services. (See Tables 3.6 and 3.7.)

Infrared, Visible, and Ultraviolet Light

The portion of the spectrum visible to the eye covers the gamut of transmitted colors ranging from red, through yellow, green, cyan, and blue. It is bracketed by infrared on the low-frequency side and ultraviolet (UV) on the high side. Infrared signals are used in a variety of consumer and industrial equipments for remote controls and sensor circuits in security systems. The most common use of UV waves is for excitation of phosphors to produce visible illumination.

X-Rays

Medical and biological examination techniques and industrial and security inspection systems are the best-known applications of X-rays. X-rays in the higher-frequency range are classified as *hard X-rays* or *gamma rays*. Exposure to X-rays for long periods can result in serious irreversible damage to living cells or organisms.

Table 3.6 Applications in the Microwave Bands (*From [1]. Used with permission.*)

Aeronavigation:	0.96–1.215 GHz
Global positioning system (GPS) down link:	1.2276 GHz
Military communications (COM)/radar:	1.35–1.40 GHz
Miscellaneous COM/radar:	1.40–1.71 GHz
L-band telemetry:	1.435–1.535 GHz
GPS downlink:	1.57 GHz
Military COM (troposcatter/telemetry):	1.71–1.85 GHz
Commercial COM and private line of sight (LOS):	1.85–2.20 GHz
Microwave ovens:	2.45 GHz
Commercial COM/radar:	2.45–2.69 GHz
Instructional television:	2.50–2.69 GHz
Military radar (airport surveillance):	2.70–2.90 GHz
Maritime navigation radar:	2.90–3.10 GHz
Miscellaneous radars:	2.90–3.70 GHz
Commercial C-band satellite (SAT) COM downlink:	3.70–4.20 GHz
Radar altimeter:	4.20–4.40 GHz
Military COM (troposcatter):	4.40–4.99 GHz
Commercial microwave landing system:	5.00–5.25 GHz
Miscellaneous radars:	5.25–5.925 GHz
C-band weather radar:	5.35–5.47 GHz
Commercial C-band SAT COM uplink:	5.925–6.425 GHz
Commercial COM:	6.425–7.125 GHz
Mobile television links:	6.875–7.125 GHz
Military LOS COM:	7.125–7.25 GHz
Military SAT COM downlink:	7.25–7.75 GHz
Military LOS COM:	7.75–7.9 GHz
Military SAT COM uplink:	7.90–8.40 GHz
Miscellaneous radars:	8.50–10.55 GHz
Precision approach radar:	9.00–9.20 GHz
X-band weather radar (and maritime navigation radar):	9.30–9.50 GHz
Police radar:	10.525 GHz
Commercial mobile COM [LOS and electronic news gathering (ENG)]:	10.55–10.68 GHz
Common carrier LOS COM:	10.70–11.70 GHz
Commercial COM:	10.70–13.25 GHz
Commercial Ku-band SAT COM downlink:	11.70–12.20 GHz
Direct broadcast satellite (DBS) downlink and private LOS COM:	12.20–12.70 GHz
ENG and LOS COM:	12.75–13.25 GHz
Miscellaneous radars and SAT COM:	13.25–14.00 GHz
Commercial Ku-band SAT COM uplink:	14.00–14.50 GHz
Military COM (LOS, mobile, and Tactical):	14.50–15.35 GHz
Aeronavigation:	15.40–15.70 GHz
Miscellaneous radars:	15.70–17.70 GHz
DBS uplink:	17.30–17.80 GHz

Table 3.6 Applications in the Microwave Bands (continued)

Common carrier LOS COM:	17.70–19.70 GHz
Commercial COM (SAT COM and LOS):	17.70–20.20 GHz
Private LOS COM:	18.36–19.04 GHz
Military SAT COM:	20.20–21.20 GHz
Miscellaneous COM:	21.20–24.00 GHz
Police radar:	24.15 GHz
Navigation radar:	24.25–25.25 GHz
Military COM:	25.25–27.50 GHz
Commercial COM:	27.50–30.00 GHz
Military SAT COM:	30.00–31.00 GHz
Commercial COM:	31.00–31.20 GHz
Navigation radar:	31.80–33.40 GHz
Miscellaneous radars:	33.40–36.00 GHz
Military COM:	36.00–38.60 GHz
Commercial COM:	38.60–40.00 GHz

3.2 Radio Wave Propagation

To visualize a radio wave, consider the image of a sine wave being traced across the screen of an oscilloscope [2]. As the image is traced, it sweeps across the screen at a specified rate, constantly changing amplitude and phase with relation to its starting point at the left side of the screen. Consider the left side of the screen to be the antenna, the horizontal axis to be distance instead of time, and the sweep speed to be the speed of light, or at least very close to the speed of light, and the propagation of the radio wave is visualized. To be correct, the traveling, or propagating, radio wave is really a wavefront, as it comprises an electric field component and an orthogonal magnetic field component. The distance between wave crests is defined as the *wavelength* and is calculated by,

$$\lambda = \frac{c}{f} \quad (3.1)$$

where:

λ = wavelength, m

c = the speed of light, approximately 2.998×10^8 m/s

f = frequency, Hz

At any point in space far away from the antenna, on the order of 10 wavelengths or 10 times the aperture of the antenna to avoid *near-field effects*, the electric and magnetic fields will be orthogonal and remain constant in amplitude and phase in relation to any other point in space. The polarization of the radio wave is defined by the polarization of the electric field, horizontal if parallel to the Earth's surface and vertical if perpendicu-

Table 3.7 Satellite Frequency Allocations (*From [1]. Used with permission.*)

Band	Uplink	Downlink	Satellite Service
VHF		0.137–0.138	Mobile
VHF	0.3120–0.315	0.387–0.390	Mobile
L-Band		1.492–1.525	Mobile
	1.610–1.6138		Mobile, Radio Astronomy
	1.613.8–1.6265	1.6138–1.6265	Mobile LEO
	1.6265–1.6605	1.525–1.545	Mobile
		1.575	Global Positioning System
		1.227	GPS
S-Band	1.980–2.010	2.170–2.200	MSS. Available Jan. 1, 2000
	(1.980–1.990)		(Available in U.S. in 2005)
	2.110–2.120	2.290–2.300	Deep-space research
		2.4835–2.500	Mobile
C-Band	5.85–7.075	3.4–4.2	Fixed (FSS)
	7.250–7.300	4.5–4.8	FSS
X-Band	7.9–8.4	7.25–7.75	FSS
Ku-Band	12.75–13.25	10.7–12.2	FSS
	14.0–14.8	12.2–12.7	Direct Broadcast (BSS) (U.S.)
Ka-Band		17.3–17.7	FSS (BSS in U.S.)
			22.55–23.55 Intersatellite
			24.45–24.75 Intersatellite
			25.25–27.5 Intersatellite
	27–31	17–21	FSS
Q	42.5–43.5, 47.2–50.2	37.5–40.5	FSS, MSS
	50.4–51.4		Fixed
		40.5–42.5	Broadcast Satellite
V	54.24–58.2		Intersatellite
	59–64		Intersatellite

Sources: Final Acts of the World Administrative Radio Conference (WARC-92), Malaga–Torremolinos, 1992; 1995 World Radiocommunication Conference (WRC-95). Also, see Gagliardi, R.M. 1991. *Satellite Communications*, van Nostrand Reinhold, New York. Note that allocations are not always global and may differ from region to region in all or subsets of the allocated bands.

lar to it. Typically, polarization can be determined by the orientation of the antenna radiating elements.

An *isotropic antenna* is one that radiates equally in all directions. To state this another way, it has a gain of unity.

If this isotropic antenna is located in an absolute vacuum and excited with a given amount of power at some frequency, as time progresses the radiated power must be equally distributed along the surface of an ever expanding sphere surrounding the isotropic antenna. The power density at any given point on the surface of this imaginary sphere is simply the radiated power divided by the surface area of the sphere, that is:

$$P_d = \frac{P_t}{4\pi D^2} \quad (3.2)$$

where:

P_d = power density, W/m²

D = distance from antenna, m

P_t = radiated power, W

Because power and voltage, in this case power density and electric field strength, are related by impedance, it is possible to determine the electric field strength as a function of distance given that the impedance of free space is taken to be approximately 377 Ω ,

$$E = \sqrt{Z P_d} = 5.48 \frac{\sqrt{P_t}}{D} \quad (3.3)$$

where E is the electric field strength in volts per meter.

Converting to units of kilowatts for power, the equation becomes

$$E = 173 \frac{\sqrt{P_{t(kW)}}}{D} \text{ V/m} \quad (3.4)$$

which is the form in which the equation is usually seen. Because a half-wave dipole has a gain of 2.15 dB over that of an isotropic radiator (dBi), the equation for the electric field strength from a half-wave dipole is

$$E = 222 \frac{\sqrt{P_{t(kW)}}}{D} \text{ V/m} \quad (3.5)$$

From these equations it is evident that, for a given radiated power, the electric field strength decreases linearly with the distance from the antenna, and power density decreases as the square of the distance from the antenna.

3.2.1 Free Space Path Loss

A typical problem in the design of a radio frequency communications system requires the calculation of the power available at the output terminals of the receive antenna [2]. Although the gain or loss characteristics of the equipment at the receiver and transmitter sites can be ascertained from manufacturer's data, the effective loss between the two antennas must be stated in a way that allows for the characterization of the transmission path between the antennas. The ratio of the power radiated by the transmit antenna to the power available at the receive antenna is known as the *path loss* and is usually expressed in decibels. The minimum loss on any given path occurs between two antennas when there are no intervening obstructions and no ground